

Finite element simulations

We performed finite element (FE) simulations for wrinkling in planar and circular bilayered structures (i.e., a thin film bonded on a substrate) to investigate the thickness variation in the buckled film. The bilayer structures were assumed to be under 2D plane strain deformation. The elastic properties of both film and substrate are described by the incompressible neo-Hookean model, whose strain energy can be expressed as

$$U = \frac{1}{2}\mu(I_1 - 3), \quad (1)$$

where μ is the shear modulus and I_1 represents the first invariant of the deformation gradient tensor \mathbf{F} . All of the FE simulations were performed with ABAQUS standard solver. The bilayered structures were discretized with CPE6MH element with the smallest mesh size less than 10% of the film thickness. To simulate the buckling behaviors due to differential growth in the film and substrate, an isotropic growth deformation was applied to the film through the “expansion” function in ABAQUS. A random perturbation (white Gaussian noise with mean magnitude equal to 0.1% of the initial film thickness) was applied to the nodal positions at the top surface to trigger the wrinkle instability.

Thickness calculations in FE simulations

The film thickness in the wrinkled state is approximated as the shortest distance between the FE nodes at the inner and outer surface of the film, as shown in Fig. 1. We observe some noise in these thickness data, which can be attributed to the finite size of the FE mesh. However, this noise is a second order perturbation and will not change the overall thickness variation of the film. The film thickness variation is compared to the substrate deformation in Fig. 2.

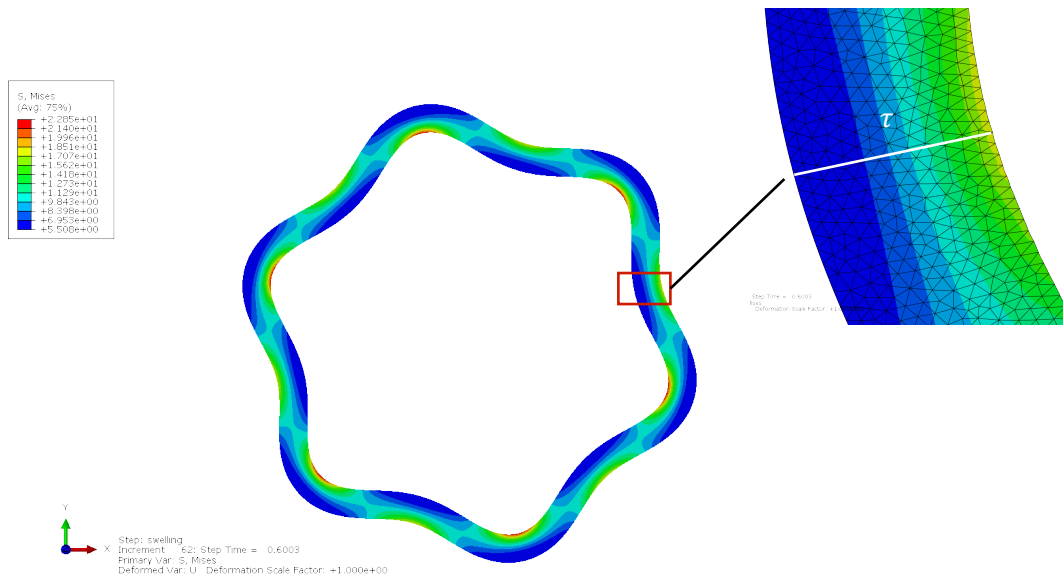


FIG. 1. Detail of film thickness measurement.

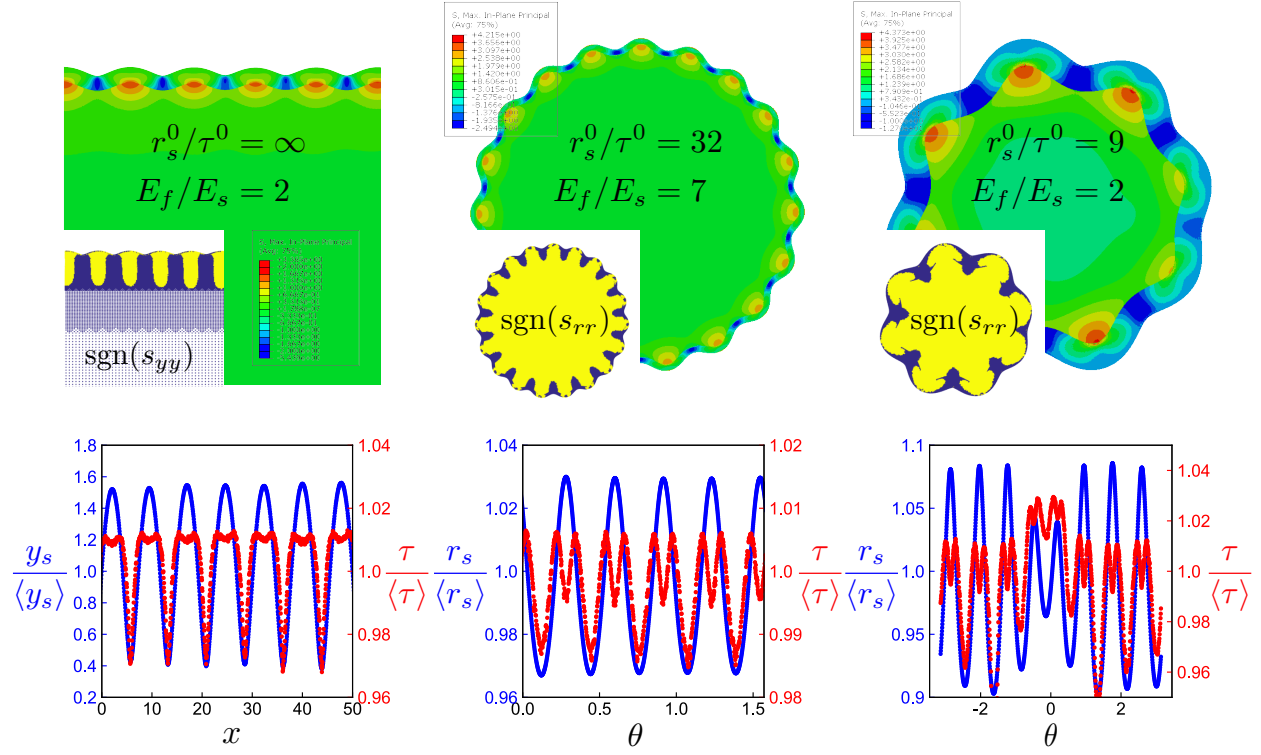


FIG. 2. Bilayer wrinkling simulations, similar to those shown in Fig. 1 of the main text, but with different geometries and modulus ratios. Top row: maximum in-plane principal stress. Insets show the sign of the stress tensor component in the direction of the surface normal, with yellow indicating positive values (tension) and purple indicating negative values (compression). Bottom row: substrate height (blue) and film thickness (red), normalized to their average values. The rightmost case with a relatively thick film shows a rotational symmetry breaking that may be indicative of global buckling.